Call for Papers and OPEN special issue For Microelectronic Engineering

Micro/Nano Devices and Systems

Short title: MicroNanoDevSystems 2017

including selected papers from the

43rd Micro- and Nano-Engineering conference MNE 2017

and from the Symposium on "Processes and Materials for Nanoelectronics" of EUROMAT 2017 conference

The aim of this special issue is to bring together recent advances in Micro/Nano Devices and Systems. This issue is 'open call'. This means that, while mainly including selected papers presented at MNE 2017 and at the 'Processes and Materials for Nanoelectronics' Symposium (C11) of EUROMAT 2017, it is also open to other authors.

The MNE conference series focuses on micro- & nanofabrication and manufacturing using lithography and other approaches related to micro- and nanopatterning, as well as the application of micro- and nanostructures and devices in electronics, photonics, electromechanics, environment, and life sciences.

The areas of particular interest for this special issue are:

Micro/Nano Devices and Systems

for applications and research outside bio/life sciences

- **MEMS/NEMS and integration:** RF-MEMS, MOEMS, surface- and bulk-micromachining, timekeeping devices, energy harvesters, key enabling technologies, heterogeneous integration, back-end-of-line
- Assembling and packaging technology: materials, testing, reliability
- **Micro/Nano devices for physical science:** nano-electronics, single electron transistor devices, quantum computer, photonic and plasmonic devices, devices based on advanced materials (e.g. metamaterials), 'Morethan-Moore' devices including processes and materials for their fabrication.
- Applications: sensors, actuators, data storage (magnetic devices, optical storage), others

Manuscript submission deadline: 13 October 2017

Manuscripts of the special issues will be submitted and reviewed via the online Elsevier Editorial System (EES). Articles will be processed and published with the standard Elsevier publishing timeline for each individual manuscript following acceptance. Please submit papers directly using the MEE journal submission web page and select the appropriate special issue. The submission opens on 6 September 2017.

Guest Editors

Santos Merino (IK4 Techniker, Eibar, Spain)
Nuria Barniol (Universidad Autonoma Barcelona, Spain)
Alain Claverie (CEMES-CNRS, France)

Instructions for authors

- The standard submitted manuscripts are regular MEE publications (4-6 pages).
- Review papers (7-10 pages) are encouraged from invited/plenary speakers and leading members of the
 community. If you are not an MNE invited speaker and you wish to submit a review, please contact <u>Evangelos</u>
 <u>Gogolides</u> (Editor-in-Chief, Microelectronic Engineering) or one of the Guest Editors with a proposal & outline.
- Highly novel work can be submitted as an accelerated publication (up to 4 pages) and will be given high priority.
- For all publications, we encourage you to include supplementary data and audio/video abstracts.
- For general enquiries, please contact the MNE Program Chair.
- Please select the correct file type (regular paper, review paper, etc.) and choose the correct name of the special issue **MicroNanoDevSystems 2017**.

Your paper and associated supplementary information should comprise a complete, novel and full description of your work. Please make sure that your paper is well-written, and supply additional information, videos, audios, etc. as on-line supplementary material to appear on the web, but not in the printed version (see instructions for authors). Your supplementary material will be available directly from ScienceDirect or Scopus.

Please note that the special issue papers undergo the same high-standard review process as any other MEE paper. At least two reviews need to be in agreement per paper before decision, and the typical rejection rate is 50-60%. Therefore, please make sure that both the technical content of your paper, and your presentation style and language, is of high quality, novel, unpublished, and not being submitted elsewhere. Please check the <u>author guidelines</u>.